

MOS FIELD EFFECT TRANSISTOR μ PA1710A

SWITCHING P-CHANNEL POWER MOS FET INDUSTRIAL USE

DESCRIPTION

This product is P-Channel MOS Field Effect Transistor designed for DC/DC converter and power management applications of notebook computers.

FEATURES

· Low on-resistance

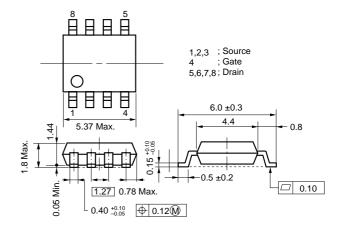
 $R_{DS(on)1} = 70 \text{ m}\Omega \text{ (MAX.) (VGS} = -10 \text{ V, ID} = -2.5 \text{ A)}$ $R_{DS(on)2} = 160 \text{ m}\Omega \text{ (MAX.) (VGS} = -4 \text{ V, ID} = -2.0 \text{ A)}$

- Low Ciss : Ciss = 840 pF (TYP.)
- Built-in G-S protection diode
- Small and surface mount package (Power SOP8)

ORDERING INFORMATION

PART NUMBER	PACKAGE
μ PA1710AG	Power SOP8

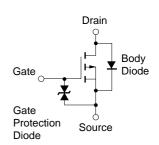
PACKAGE DRAWING (Unit: mm)



ABSOLUTE MAXIMUM RATINGS (TA = 25°C, All terminals are connected.)

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Drain to Source Voltage (Vss = 0 V)	VDSS	-30	V
Gate to Source Voltage (Vps = 0 V)	Vgss	±20	V
Drain Current (DC)	ID(DC)	±5.0	Α
Drain Current (pulse) Note1	ID(pulse)	±20	Α
Total Power Dissipation (T _A = 25° C) Note2	Рт	2.0	W
Channel Temperature	Tch	150	°C
Storage Temperature	Tstg	-55 to + 150	°C

EQUIVARENT CIRCUIT



- **Notes 1.** PW \leq 10 μ s, Duty Cycle \leq 1 %
 - 2. Mounted on ceramic substrate of 1200 mm² x 1.1 mm

Remark The diode connected between the gate and source of the transistor serves as a protector against ESD. When this device actually used, an additional protection circuit is externally required if a voltage exceeding the rated voltage may be applied to this device.

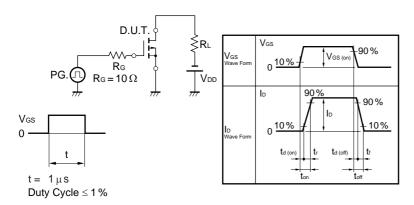
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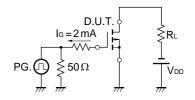
ELECTRICAL CHARACTERISTICS (TA = 25 °C, All terminals are connected.)

CHARACTERISTICS	SYMBOL	TEST CONDITIONS	MIN.	TYP.	MAX.	UNIT
Drain to Source On-state Resistance	RDS(on)1	Vgs = -10 V, ID = -2.5 A		45	70	mΩ
	RDS(on)2	Vgs = -4 V, ID = -2.0 A		91	160	mΩ
Gate to Source Cut-off Voltage	V _{GS(off)}	$V_{DS} = -10 \text{ V}, I_{D} = -1 \text{ mA}$	-1.0	-1.8	-2.5	V
Forward Transfer Admittance	yfs	V _{DS} = -10 V, I _D = -2.5 A	3.0	5.6		S
Drain Leakage Current	Inss	Vps = -30 V, Vgs = 0 V			-10	μΑ
Gate to Source Leakage Current	lgss	Vgs = ±20 V, Vps = 0 V			±10	μΑ
Input Capacitance	Ciss	Vps = -10 V		840		pF
Output Capacitance	Coss	V _G S = 0 V		570		pF
Reverse Transfer Capacitance	Crss	f = 1 MHz		190		pF
Turn-on Delay Time	td(on)	I _D = -2.5 A		13		ns
Rise Time	tr	$V_{GS(on)} = -10 \text{ V}$		66		ns
Turn-off Delay Time	td(off)	V _{DD} = -15 V		82		ns
Fall Time	t f	$R_G = 10 \Omega$		52		ns
Total Gate Charge	Q _G	ID = -5.0 A		27.3		nC
Gate to Source Charge	Qgs	V _{DD} = -24 V		2.7		nC
Gate to Drain Charge	Q _{GD}	Vgs = -10 V		8.2		nC
Body Diode Forward Voltage	VF(S-D)	IF = 5.0 A, VGS = 0 V		0.81		V
Reverse Recovery Time	trr	IF = 5.0 A, Vgs = 0 V		61		ns
Reverse Recovery Charge	Qrr	$di/dt = 50 A/ \mu s$		71		nC

TEST CIRCUIT 1 SWITCHING TIME

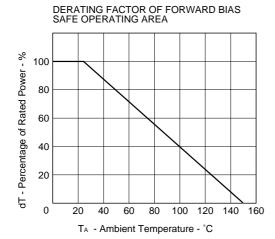


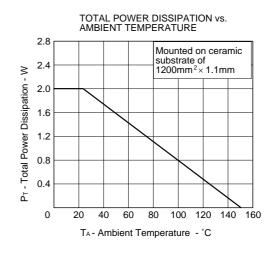
TEST CIRCUIT 2 GATE CHARGE

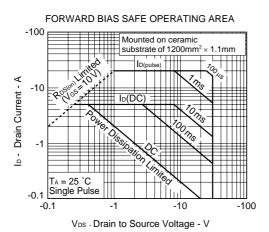


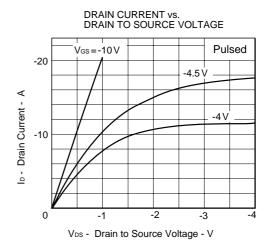


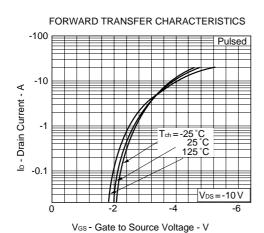
TYPICAL CHARACTERISTICS (TA = 25 °C)



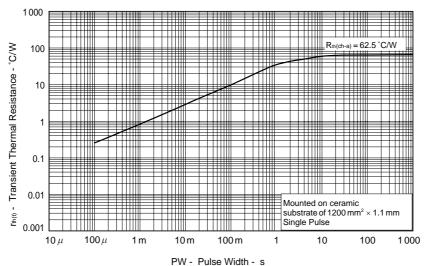




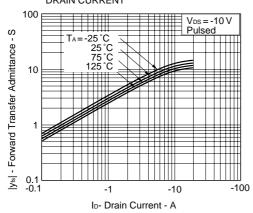




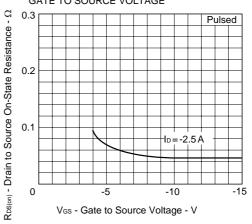
TRANSIENT THERMAL RESISTANCE vs. PULSE WIDTH



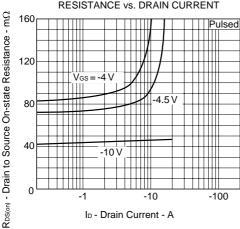
FORWARD TRANSFER ADMITTANCE vs. DRAIN CURRENT



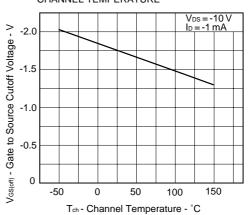
DRAIN TO SOURCE ON-STATE RESISTANCE vs. GATE TO SOURCE VOLTAGE



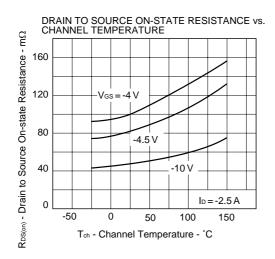
DRAIN TO SOURCE ON-STATE RESISTANCE vs. DRAIN CURRENT

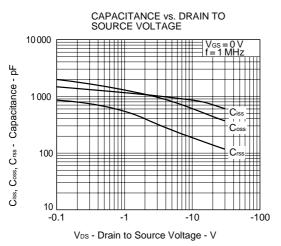


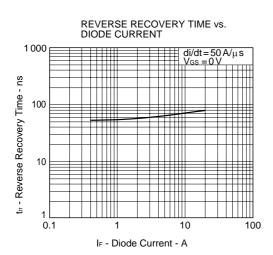
GATE TO SOURCE CUTOFF VOLTAGE vs. CHANNEL TEMPERATURE

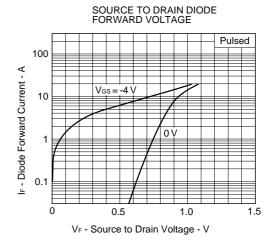


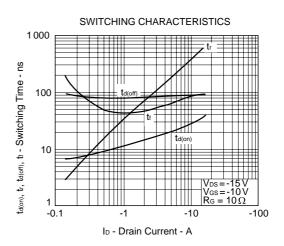


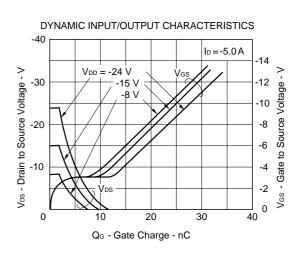












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Anti-radioactive design is not implemented in this product.

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